

**Search Notes**

Application/Control No.

10/084,641

Examiner

Wesley D. Markham

Applicant(s)/Patent under  
Reexamination

IKEDA ET AL.

Art Unit

1762

**SEARCHED**

Class	Subclass	Date	Examiner
427	162	10/13/2005	WM
	163.1		
	164		
	165		
	264		
	270		
	271		
	277		
	278		
	355		
	374.1		
	375		
	385.5		
	389.7		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
EAST search of US patent and PG pub claims		10/13/2005	WM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor and assignee search	10/13/2005	WM
EAST search, all DBs (see search strategy printouts for details)		
Interference search terms: resin, curing, glass transition temperature, polymerize, stamp, emboss, pattern, microasperity,		
baking, alignment film, and variations and combinations thereof		

**Search Notes (continued)**

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**SEARCHED**

Class	Subclass	Date	Examiner
264	1.1	10/13/2005	WM
	1.31		
	1.34		
	1.7		
	1.9		
349	67		
	113		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR